

**Notice of References Cited**

Application/Control No.

10/594,708

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

ROBERT CABRAL

Art Unit

1618

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**U.S. PATENT DOCUMENTS**

★		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

★		Document Number	Date	Country	Name	Classification
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	N					
	O					
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	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

★		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Ishikawa et al., "Structure and electrical properties of Au <sub>2</sub> S," Solid State Ionics 79 (1995) 60-66			
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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